

IN THE CLAIMS:

1. A Flash EEPROM system comprising:  
one or more integrated circuit chips each  
having an array of Flash EEPROM cells partitioned into  
a plurality of sectors, each sector addressable for  
erase such that all cells therein are erasable  
simultaneously;

means for selecting a plurality of sectors among the one or more chips for erase operation; and  
means for simultaneously performing the erase operation on only the plurality of selected sectors.

2. A Flash EEprom system as in claim 1, including read or write operations on chips which have been enabled by a chip select signal, wherein the erase operation is performed on chips without regard to the chip select signal.

3. A Flash EEPROM system as in claim 1, wherein the erase operation may be performed on the plurality of sector selected for erase operation, while read, write or other operations may be performed on any other device not selected for erase operation.

4. The Flash EEprom system according to claim 1, further comprising:  
means for individually removing any one or combination of sectors from the plurality of selected sectors, such that said removed sectors are prevented from further erase during the erase operation.

means for substituting one or more of the defective cells with a corresponding number of substitute cells.

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10 15. A system for correcting errors from defective cells within an array of Flash EEprom cells as in claim 10, said array being partitioned into a plurality of Flash erasable sectors such that all cells within each sector are erasable at once, wherein the substitute cells are in the same sector as the defective cells when the number of defective cells in the sector does not exceed a predetermined number, and the substitute cells are in a different sector when the number is exceeded.

5 16. A system for correcting errors from defective cells within an array of Flash EEprom cells as in claim 15, wherein said sector is replaced in its entirety by a substitute sector when said number is exceeded.

5 17. A system for correcting errors from defective cells within an array of Flash EEprom cells as in claim 15 wherein the substituting means also applies automatically new defective cells as soon as they are detected.

18. A system for correcting errors from defective cells within an array of Flash EEprom cells as in claim 17, including the use of error correction codes.

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5       substitute cells for storing good data intended  
for the defective cells;

20. A system for correcting bad data in defective cells within an array of Flash EEprom cells as in claim 19, further comprising means for automatically saving the good data intended to be written to the defective cells to the corresponding substitute cells, thereby perserving the integrity of the good data.

22. A system for correcting bad data in defective cells within an array of Flash EEprom cells as in claim 20, said array being partitioned into a plurality of Flash erasable sectors such that all cells within each sector are erasable at once, and data is stored therein, wherein the substituting means applies after the data including the bad data has been accessed.

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automatically to newly occurring defective cells.

in claim 28, including use of error correction codes.

into a Flash EEprom memory comprising:

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memory instead of the Flash EEPROM memory;

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file was last written; and

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means responsive to an impending power loss for down loading the data files in the cache memory to the backup memory, thereby saving the data files from the possibly volatile cache memory.

33. The improved system as in claim 30, wherein the cache memory has a significantly faster access time than that of the Flash EEprom memory.

35. The improved system as in claim 30, including a microprocessor system and random access memory, wherein the improved system is implemented by software in the microprocessor system with random access memory.



36. An improved system for writing data files into a Flash EEPROM memory comprising:

5 a cache memory for temporarily storing data files intended for the Flash EEPROM memory, said cache memory able to undergo significantly more write/erase cycles than the Flash EEPROM memory;

means responsive to a system write to the Flash EEPROM memory for writing data files into the cache memory instead of the Flash EEPROM memory;

10 a tag memory for storing the identity of data files and the time each data file was last written; and

15 means for first moving data file having the longest time since last written from the cache memory to the Flash EEPROM memory when additional space for new data files is required in the cache memory, thereby substantially reducing the number of actual writes and associated stress to the Flash EEPROM memory.

37. The improved system as in claim 36, further comprising:

a backup non-volatile memory for downloading the data files in the cache memory thereto; and

5 means responsive to an impending power loss for downloading the data files in the cache memory to the backup memory, thereby saving the data files from the possibly volatile cache memory.

38. The improved system as in claim 36, wherein the backup memory is part of the Flash EEPROM memory.

39. The improved system as in claim 36, wherein the cache memory has a significantly faster access time than that of the Flash EEPROM memory.

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41. The improved system as in claim 36, including a microprocessor system and random access memory, wherein the improved system is implemented by software in the microprocessor system with random access memory.

a cache memory for temporarily storing data files intended for the Flash EEprom memory, said cache memory able to undergo significantly more write/erase cycles than the Flash EEprom memory;

means responsive to a system write to the Flash  
EEProm memory for writing a data file either into the  
Flash EEPROM memory or instead into the cache memory,  
said responsive means writing to the Flash EEPROM when  
the a previous copy of said data file is not present in  
the cache memory, and writing to the cache memory when  
a previous copy of said data file is present in the  
cache memory; and

means for first moving data files having the longest times since last written from the cache memory to the Flash EEprom memory when additional space for new data files is required in the cache memory, thereby substantially reducing the number of actual writes and associated stress to the Flash EEprom memory.

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49. The improved system as in claim 46, including a microprocessor system and random access memory, wherein the improved system is implemented by software in the microprocessor system with random access memory.

5 a cache memory for temporarily storing data files intended for the Flash EEprom memory, said cache memory able to undergo significantly more write/erase cycles than the Flash EEprom memory;

means responsive to a system write to the Flash  
10   EEProm memory for writing a data file either into the  
Flash EEPROM memory or instead into the cache memory,  
said responsive means writing to the Flash EEPROM when  
the data file is not identified in the tag memory, and  
writing to the cache memory when the data file is  
15   identified in the tag memory; and

51. The improved system as in claim 50,  
further comprising:

5 means responsive to an impending power loss for down loading the data files in the cache memory to the backup memory, thereby saving the data files from the possibly volatile cache memory.

52. The improved system as in claim 50, wherein the backup memory is part of the Flash EEPROM memory.

53. The improved system as in claim 50, wherein the cache memory has a significantly faster access time than that of the Flash EEprom memory.

54. The improved system as in claim 50, including a controller circuit chip for controlling the operations of the Flash EEprom memory, wherein the improved system is part of the controller circuit chip.

55. The improved system as in claim 50, including a microprocessor system and random access memory, wherein the improved system is implemented by software in the microprocessor system with random access memory.

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means responsive to an unsuccessful attempt to either program or erase a storage cell within one of said sectors for substituting one of said spare storage cells therefore while maintaining operation of the remaining cells of said sector.

57. The memory card according to claim 56 which additionally comprises a cache memory mounted on said card, and wherein said programming means includes means for initially programming said cache memory rather than <sup>AB</sup>said EEPROM memory, said reading means includes means for initially determining whether the cache memory contains data to be read, and said programming means additionally includes means responsive to said cache memory becoming full for writing its oldest unused block of data into said EEPROM memory, thereby to make room for new data in said cache memory.

58. The memory card as in claim 56, wherein each of said chips further includes a plurality of spare sectors, and wherein said substituting means also substitutes one of said spare sectors for one of said sectors when a predetermined number of cells in said one of said sectors become defective.

59. The memory card as in claim 58, including means for performing error correction using error correction codes.

60. The memory card as in claim 56, including a controller and an interface connected to the system bus, said controller being adapted to be responsive to commands intended for a standard magnetic disk drive storage system connectable to the computer system, thereby emulating said disk drive system.

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61. The memory card as in claim 56, in which various operating voltages are required for various operations of the EEprom chips, including means for generating the various operating voltages from the standard power supply.

62. A storage system incorporating therein the memory card of claim 56, comprising:

a controller for controlling <sup>AB</sup>the operation of the EEprom chips;

means for generating voltages for <sup>AB</sup>the operation of the EEprom chips;

means for error correction in <sup>AB</sup>the operation of the storage system; and

means for interfacing the storage system to a computer system.

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